

Application No. 10/612,037  
Response to Office Action

Customer No. 01933

**Listing of Claims:**

1. (Currently Amended) An optical gain correction filter comprising:

a multilayer film structure formed by stacking a plurality of thin films with different ~~diffraction~~ refractive indices on a light transmitting board,

5 wherein when ~~the~~ light with ~~the~~ a wavelength  $\lambda$  enters at the an incident angle  $\theta$ , ~~the~~ a transmissivity is assumed to be  $T_1(\lambda, \theta)$  ( $0 \leq T_1(\lambda, \theta) \leq 1$ ), and ~~the~~ a thickness of each thin film is set to increase the transmissivity  $T_1(\lambda_0, \theta)$  when the  
10 incident angle  $\theta$  increases close to ~~the~~ a predetermined maximum incident angle  $\theta_{max}$  with respect to the incident light with ~~the~~ a wavelength  $\lambda_0$  entering the multilayer film structure.

2. (Currently Amended) The optical gain correction filter according to claim 1, wherein the plurality of thin films ~~which construct the multilayer film structure are formed by~~  
comprise alternately stacking stacked  $\text{SiO}_2$  films with ~~the~~ a  
5 refractive index of 1.46 and  $\text{TiO}_2$  films with ~~the~~ a refractive index of 2.3.

3. (Currently Amended) The optical gain correction filter according to claim 2, ~~having~~ wherein the transmissivity ~~of~~ is not

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more than 70% or lower so that the wavelength  $\lambda_0$  of the incident light coincides with ~~the~~ a position of a ripple of a band pass filter.

4. (Currently Amended) The optical gain correction filter according to claim 1, wherein the thin films ~~which construct the multilayer film structure are formed by~~ comprise alternately combining stacked (a) films made from one of  $\text{SiO}_2$ ,  $\text{MgF}_2$ ,  $\text{Al}_2\text{O}_3$  or and SiO and (b) films made from one of  $\text{TiO}_2$ ,  $\text{CeO}_2$ ,  $\text{ZrO}_2$ ,  $\text{Ta}_2\text{O}_5$  or and ZnS.

5. (Currently Amended) An optical gain correction filter comprising:

a multilayer film structure formed by stacking a plurality of thin films with different ~~diffraction indexes~~ refractive

indices on a light transmitting board, wherein

when ~~the~~ light with ~~the~~ a wavelength  $\lambda$  enters at ~~the~~ an incident angle  $\theta$  ~~the~~ a transmissivity is assumed to be  $T_1(\lambda, \theta)$  ( $0 \leq T_1(\lambda, \theta) \leq 1$ ), and ~~the~~ a thickness of each thin film is set to increase the transmissivity  $T_1(\lambda, \theta_0)$  when the wavelength  $\lambda$  increases close to ~~the~~ a predetermined maximum wavelength  $\lambda_{\text{max}}$  with respect to the incident light entering the multilayer structure at ~~the~~ an incident angle of  $\theta_0$ .

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6. (Currently Amended) The optical gain correction filter according to claim 5, wherein the plurality of thin films which construct the multilayer film structure are formed by comprise alternately stacking stacked SiO<sub>2</sub> films with the a refractive index of 1.46 and TiO<sub>2</sub> films with the a refractive index of 2.3.

7. (Currently Amended) The optical gain correction filter according to claim 6, having wherein the transmissivity of is not more than 70% or lower so that the wavelength  $\lambda_0$  of the incident light coincides with the a position of a ripple of a band pass filter.

8. (Currently Amended) The optical gain correction filter according to claim 5, wherein the thin films which construct the multilayer film structure are formed by comprise alternately combining stacked (a) films made from one of SiO<sub>2</sub>, MgF<sub>2</sub>, Al<sub>2</sub>O<sub>3</sub> or and SiO and (b) films made from one of TiO<sub>2</sub>, CeO<sub>2</sub>, ZrO<sub>2</sub>, Ta<sub>2</sub>O<sub>5</sub> or and ZnS.

9. (Currently Amended) An optical gain correction filter comprising:

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a multilayer film structure formed by stacking a plurality of thin films with different ~~diffraction indexes~~ refractive  
5 indices on a light ~~transmitting reflecting~~ board,

wherein when the light with the a wavelength  $\lambda$  enters at the an incident angle  $\theta$ , the a reflectivity is assumed to be  $R_1(\lambda, \theta)$  ( $0 \leq R_1(\lambda, \theta) \leq 1$ ), and the a thickness of each thin film is set to increase the reflectivity  $R_1(\lambda_0, \theta)$  when the incident  
10 angle  $\theta$  increases close to the a predetermined maximum incident angle  $\theta_{\max}$  with respect to the incident light with the a wavelength  $\lambda_0$  entering the multilayer film structure.

10. (Currently Amended) The optical gain correction filter according to claim 9, wherein the plurality of thin films which ~~construct the multilayer film structure are formed by~~  
comprise alternately ~~stacking~~ stacked SiO<sub>2</sub> films with the a refractive index of 1.46 and TiO<sub>2</sub> films with the a refractive  
5 index of 2.3.

11. (Currently Amended) The optical gain correction filter according to claim 10, ~~having wherein the transmissivity of~~  
reflectivity is not more than 70% or lower so that the wavelength  $\lambda_0$  of the incident light coincides with the a position of a ripple of a band pass filter.

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12. (Currently Amended) The optical gain correction filter according to claim 9, wherein the thin films ~~which construct the multilayer film structure are formed by~~ comprise alternately ~~combining~~ stacked (a) films made from one of  $\text{SiO}_2$ ,  $\text{MgF}_2$ ,  $\text{Al}_2\text{O}_3$  ~~or~~ and  $\text{SiO}$  and (b) films made from one of  $\text{TiO}_2$ ,  $\text{CeO}_2$ ,  $\text{ZrO}_2$ ,  $\text{Ta}_2\text{O}_5$  ~~or~~ and  $\text{ZnS}$ .

13. (Currently Amended) An optical gain correction filter comprising:

a multilayer film structure formed by stacking a plurality of thin films with different ~~diffractive indexes~~ refractive indices on a light ~~transmitting~~ reflecting board,

wherein when ~~the~~ light with ~~the~~ a wavelength  $\lambda$  enters at the an incident angle  $\theta$ , ~~the~~ a reflectivity is assumed to be  $R_1(\lambda, \theta)$  ( $0 \leq R_1(\lambda, \theta) \leq 1$ ), and ~~the~~ a thickness of each thin film is set to increase the reflectivity  $R_1(\lambda, \theta_0)$  when the wavelength  $\lambda$  increases close to the a predetermined maximum wavelength  $\lambda_{\text{max}}$  ~~wit~~ with respect to the incident light entering the multilayer structure at the an incident angle of  $\theta_0$ .

14. (Currently Amended) The optical gain correction filter according to claim 13, wherein the plurality of thin films ~~which construct the multilayer film structure are formed by~~

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5 comprise alternately ~~stacking~~ stacked  $\text{SiO}_2$  films with the a refractive index of 1.46 and  $\text{TiO}_2$  films with the a refractive index of 2.3.

15. (Currently Amended) The optical gain correction filter according to claim 14, ~~having wherein the transmissivity of~~ reflectivity is not more than 70% or lower so that the wavelength  $\lambda_0$  of the incident light coincides with the a position of a ripple of a band pass filter.

5 16. (Currently Amended) The optical gain correction filter according to claim 14, wherein the thin films ~~which construct the multilayer film structure are formed by~~ comprise alternately ~~combining~~ stacked (a) films made from one of  $\text{SiO}_2$ ,  $\text{MgF}_2$ ,  $\text{Al}_2\text{O}_3$  or and  $\text{SiO}$  and (b) films made from one of  $\text{TiO}_2$ ,  $\text{CeO}_2$ ,  $\text{ZrO}_2$ ,  $\text{Ta}_2\text{O}_5$  or and  $\text{ZnS}$ .

17. (Currently Amended) An optical apparatus comprising:  
[[,]]

a semiconductor laser light source ~~with the~~ which emits a laser beam having a wavelength of  $\lambda_0$ ;

5 a scanning section for scanning a the laser beam radiated from the semiconductor laser light source;

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a photodetector for receiving scattered light from the scanned laser beam; and

an optical gain correction filter, which is arranged on an optical path from the semiconductor laser light source to the photodetector, and ~~has~~ which comprises a multilayer film structure formed by stacking a plurality of thin films with different ~~diffraction indexes~~ refractive indices on a light transmitting board; ~~in which~~

wherein when light with the a wavelength  $\lambda$  enters at the an incident angle  $\theta$ , ~~the~~ a transmissivity is assumed to be  $T_1(\lambda, \theta)$  ( $0 \leq T_1(\lambda, \theta) \leq 1$ ), and ~~the~~ a thickness of said each thin film is set to increase the transmissivity  $T_1(\lambda_0, \theta)$  when the incident angle  $\theta$  increases close to ~~the~~ a predetermined maximum incident angle  $\theta_{\max}$  with respect to the incident light with the a wavelength  $\lambda_0$  entering the multilayer film structure; and

wherein the optical gain correction filter is arranged in ~~the direction~~ to increase the transmissivity  $T_1(\lambda, \theta)$  as ~~the~~ an incident angle of the scattered light increases.

18. (Currently Amended) The optical apparatus according to claim 17, wherein the optical gain correction filter is provided ~~on the optical path, and one of:~~ on the a reflection surface of the scanning section, ~~or~~ and in front of the photodetector.

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19. (Currently Amended) An optical apparatus comprising:

[[,]]

a semiconductor laser light source ~~with the~~ which emits a laser beam having a wavelength of  $\lambda_0$ ;

5 a scanning section for scanning ~~a~~ the laser beam radiated from the semiconductor laser light source;

a photodetector for receiving scattered light from the scanned laser beam; and

10 an optical gain correction filter, which is arranged on an optical path from the semiconductor laser light source to the photodetector, and ~~has~~ which comprises a multilayer film structure formed by stacking a plurality of thin films with different ~~diffraction indexes~~ refractive indices on a light emitting reflecting board; ~~in which~~

15 wherein when light with ~~the~~ a wavelength  $\lambda$  enters at the an incident angle  $\theta$  ~~the~~ a transmissivity is assumed to be  $T_1(\lambda, \theta)$  ( $0 \leq T_1(\lambda, \theta) \leq 1$ ), and ~~the~~ a thickness of said each thin film is set to increase the transmissivity  $T_1(\lambda, \theta_0)$  when the wavelength  $\lambda$  increases close to ~~the~~ a predetermined maximum wavelength  $\lambda_{\max}$  with respect to the incident light entering the

20 multilayer structure at ~~the~~ an incident angle of  $\theta_0$ ; and

wherein the optical gain correction filter is arranged ~~in the direction~~ to increase the transmissivity  $T_1(\lambda, \theta)$  as ~~the~~ an incident angle of the scattered light increases.



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20. (Currently Amended) The optical apparatus according to claim 19, wherein the optical gain correction filter is provided ~~on the optical path, and one of:~~ on the a reflection surface of the scanning section, ~~or and~~ in front of the photodetector.

21. (Currently Amended) An optical apparatus comprising:  
[[,]]

a semiconductor laser light source ~~with the~~ which emits a laser beam having a wavelength of  $\lambda_0$ ;

a scanning section for scanning ~~a~~ the laser beam radiated from the semiconductor laser light source;

a photodetector for receiving scattered light from the scanned laser beam; and

an optical gain correction filter, which is arranged on an optical path from the semiconductor laser light source to the photodetector, and ~~has~~ which comprises a multilayer film structure formed by stacking a plurality of thin films with different ~~diffraction indexes~~ refractive indices on a light reflecting board; ~~to transmit a light, in which~~

wherein when ~~a~~ light with ~~the~~ a wavelength  $\lambda$  enters at ~~the~~ an incident angle  $\theta$ , ~~the~~ a reflectivity is assumed to be  $R_1(\lambda, \theta)$  ( $0 \leq R_1(\lambda, \theta) \leq 1$ ), and ~~the~~ a thickness of said each thin film is set to increase the reflectivity  $R_1(\lambda_0, \theta)$  when the

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incident angle  $\theta$  increases close to ~~the~~ a predetermined maximum incident angle  $\theta_{\max}$  with respect to the incident light with ~~the~~ a wavelength  $\lambda_0$  entering the multilayer film structure; and

wherein the optical gain correction filter is arranged ~~in~~ the direction to increase the reflectivity  $R_1(\lambda, \theta)$  as ~~the~~ an incident angle of the scattered light increases.

22. (Currently Amended) The optical apparatus according to claim 21, wherein the optical gain correction filter is provided ~~on the optical path, and one of:~~ on ~~the~~ a reflection surface of the scanning section, ~~or~~ and in front of the photodetector.

23. (Currently Amended) An optical apparatus comprising:  
[[,]]

a semiconductor laser light source ~~with the~~ which emits a laser beam having a wavelength of  $\lambda_0$ ;

a scanning section for scanning ~~a~~ the laser beam radiated from the semiconductor laser light source;

a photodetector for receiving scattered light from the scanned laser beam; and

an optical gain correction filter, which is arranged on an optical path from the semiconductor laser light source to the photodetector, and ~~has~~ which comprises a multilayer film structure formed by stacking a plurality of thin films with

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different ~~diffraction indexes~~ refractive indices on a light  
~~transmitting~~ reflecting board; ~~in which~~

wherein when light with ~~the~~ a wavelength  $\lambda$  enters at ~~the~~ an  
incident angle  $\theta$ , ~~the~~ a reflectivity is assumed to be  $R_1(\lambda, \theta)$   
( $0 \leq R_1(\lambda, \theta) \leq 1$ ), and ~~the~~ a thickness of said each thin film  
is set to increase the reflectivity  $R_1(\lambda, \theta_0)$  when the  
~~wavelength~~ wavelength  $\lambda$  increases close to ~~the~~ a predetermined  
maximum wavelength  $\lambda_{\max}$  ~~with~~ with respect to the incident light  
entering the multilayer structure at ~~the~~ an incident angle of  $\theta_0$ ;  
and

wherein the optical gain correction filter is arranged ~~in~~  
~~the direction~~ to increase the reflectivity  $R_1(\lambda, \theta)$  as ~~the~~ an  
incident angle of the scattered light increases.

24. (Currently Amended) The optical apparatus according to  
claim 23, wherein the optical gain correction filter is provided  
~~on the optical path, and one of:~~ on ~~the~~ a reflection surface of  
the scanning section, ~~or~~ and in front of the photodetector.